

#### **Features**

- Compatible with HDMI 1.3c
- Supports 2.5 Gbps signaling rate for 480i/p, 720i/p, and 1080i/p resolutions up to 12-bit color depth
- Integrated receiver termination
- Adaptive receiver equalization to accommodate to different input cable lengths
- DDC buffer link
- CEC buffer link
- Embedded memory for EDID function
- Intra-pair skew < 40 ps</li>
- Inter-pair skew < 65 ps</li>
- System Level ESD Protection Exceeds 6 kV (direct contact) for TMDS Inputs and DDC Interface
- Supply voltage, VCC= 3.3 V +/- 5%
- Controllable shutdown and standby modes for power saving
- Controllable logic states for HPD output
- 5-V tolerance on all side band signals
- 64-pin LQFP package
- Green part and 260 °C reflow rated

# **Applications**

- Digital TV
- Digital projector
- Digital monitor
- Audio/video receiver

# **Description**

The AZHW271D is a 2-port High-Definition Multimedia Interface (HDMI) or DVI switch which allows up to 2 HDMI or DVI ports to be switched to a single display terminal. Four TMDS channels, one hot plug detector, and a digital display control (DDC) interface are supported on each port. Each TMDS channel allows signaling rates up to 2.5 Gbps to allow 1080p resolution in 12-bit color depth.

With two control pins, the AZHW271D can be operated at the shutdown mode. At this condition, all TMDS input terminations are disconnected and at the state of high impedance. Moreover, the DDC links are disabled due to that all internal devices are turned off and all HPD outputs are connected to the HPD\_SINK. This allows the initiation of the HDMI physics address discovery process. Termination resistor (50- $\Omega$ ), pulled up to VCC, are integrated at each TMDS receiver input. External terminations are not required as shown in Fig.1. Moreover, the AZHW271D is the generation of the devices from Amazing

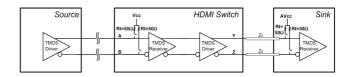


Fig.1. TMDS internal termination

to integrate the Extended Display Identification Data (EDID). The EDID is stored in on-chip memory (256 bytes) and it is built-in on each port through the DDC bus.

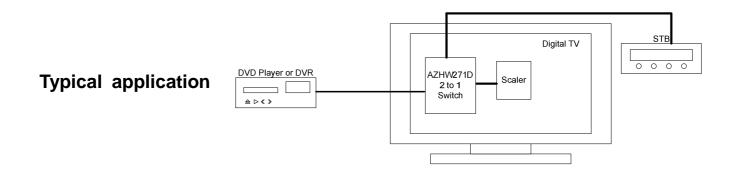
The AZHW271D provides adaptive input equalization for different ranges of cable lengths. Each TMDS receiver owns frequency responsive equalization circuits. A 0-ohm (recommended value) calibration resistor is tied to GND for EQ pin, the receiver with optimized equalization supports the connection in different range HDMI cables. Moreover, A 0-ohm (recommended value) calibration resistor is tied to GND for RP1 (pin 9) pin, the receiver of port 1 and

port 2 with adaptive equalization supports the input connection in different range HDMI cables. Also, A 100k-ohm (recommended value) calibration resistor is tied to GND for RP2 (pin 3) pin, the receiver of port 1 and port 2 with adaptive equalization supports the input connection in different range HDMI cables. The AZHW271D supports two types of power saving operations. When a system is under shutdown mode and there is no digital audio/visual content from a connected source to minimize power consumption from TMDS inputs, outputs, and internal circuits. When a system is under standby mode (PS at logic high), only TMDS clock inputs, outputs and termination are turned on, and the selected DDC repeater link from the source to sink. At this state, the system can be quick recovery as the digital audio/visual content from a connected source. Otherwise, to filter supply noise, all VCC pins are recommended to have a 0.01 uF capacitor tied from each VCC pin to ground directly. For the ESD protection function, AZHW271D is designed to withstand the

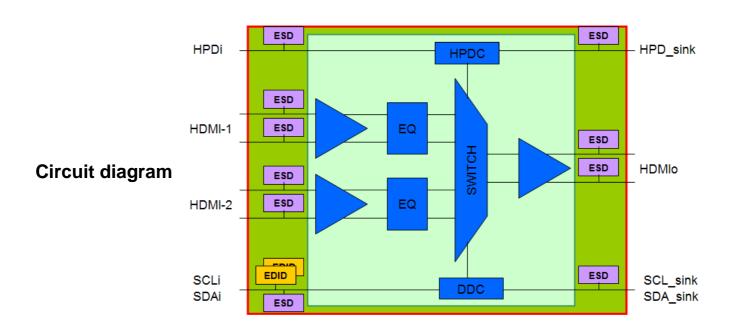
ESD level (IEC61000-4-2) to contact mode 6 kV. For the requirements of application, a higher protection level is needed. The AZHW271D can provide TMDS pairs, DDC, and HPD pins' ESD levels (IEC61000-4-2) to contact mode 6 kV. And external ESD components are not required for the criteria of ESD contact mode 6 kV.

Furthermore, the AZHW271D also provides controllable states of HPD outputs. When HPD\_ctl set high, all HPD outputs can follow HPD\_SINK. For the VSADJ pin, it is recommended to be tied a 6.2-k $\Omega$  resistor (10% precision) to control the output swing to the HDMI compliance test.

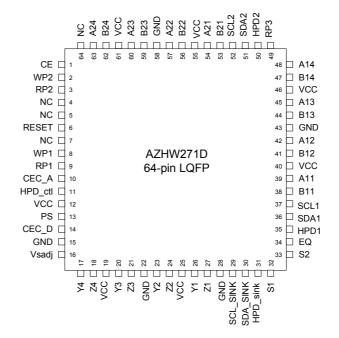
Finally, the AZHW271D also integrates an HDMI compliant I/O to enable Consumer Electronics Control (CEC) in a DTV. The CEC I/O meets all HDMI compliance test and eliminates the need for additional external components. The device is characterized for operation from 0 °C to 70 °C.







Pin Configuration





## **TERMINAL FUNCTIONS**

TERMIN	AL		Decembries	
NAME	NO.	I/O	Description	
A11, A12, A13, A14	39, 42, 45, 48	I	Source port 1 TMDS positive inputs	
A21, A22, A23, A24	54, 57, 60, 63	I	Source port 2 TMDS positive inputs	
B11, B12, B13, B14	38, 41, 44, 47	I	Source port 1 TMDS negative inputs	
B21, B22, B23, B24	53, 56, 59, 62	I	Source port 2 TMDS negative inputs	
GND	15, 22, 28, 43, 58		Ground	
EQ	34	I	TMDS input equalization calibration	
			Power saving selector	
PS	13	I	PS= highstandby mode	
			PS= lownormal mode	
			HPD output selector	
	11		HPD_ctl= highall HPD output follows	
HPD_ctl		I	HPD_SINK	
			HPD_ctl=lowonly selected HPD output	
			follows HPD_SINK	
HPD1	35	0	Source port 1 hot plug detector output	
HPD2	50	0	Source port 2 hot plug detector output	
HPD_SINK	31	I	Sink port hot plug detector input	
SCL1	37	I/O	Source port 1 DDC I <sup>2</sup> C clock line	
SCL2	52	I/O	Source port 2 DDC I <sup>2</sup> C clock line	
SCL_SINK	29	I/O	Sink port DDC I2C clock line	
SDA1	36	I/O	Source port 1 DDC I <sup>2</sup> C data line	
SDA2	51	I/O	Source port 2 DDC I <sup>2</sup> C data line	
SDA_SINK	30	I/O	Sink port DDC I <sup>2</sup> C data line	
S1, S2	32,33	Ī	Source selector	
VCC	12, 19, 25, 40,		Power supply	
V C C	46, 55, 61		Power supply	
Vsadj	16	I	TMDS compliant voltage swing control	
CEC_A	10	I/O	Source port 1,2,3,4 CEC line	
CEC_D	14	I/O	Sink port CEC line	



TERMIN	IAL		Description
NAME	NO.	I/O	Description
Y1, Y2, Y3, Y4	26, 23, 20, 17	0	Sink port TMDS positive outputs
Z1, Z2, Z3, Z4	27, 24, 21, 18	0	Sink port TMDS negative outputs
RP1	9		Calibration resistor
RP2	3		Calibration resistor
RP3	49		TMDS input equalization calibration
WP1	8	I	Write protection for port 1 EDID memory
WP2	2	I	Write protection for port 2 EDID memory
CE	1		Capacitor for memory enable function
RESET	6		Capacitor for memory reset function
NC	4, 5, 7, 64		NC pins

Table-1-1: Source Selection Lookup (Normal operation)

	CON	NTROL PINS		I/O SELECTED		HOT PLUG DETECT STATUS	
<b>S</b> 1	<b>S</b> 2	PS	HPD_ctl	Y/Z	SCL_sink SDA_sink	HPD1	HPD2
н	н	L	L	A1/B1 50 $\Omega$ Terminations are connected A2/B2 50 $\Omega$ Terminations are disconnected	SCL1 SDA1	HPD_SINK	L
L	Н	L	L	A2/B2 50 $\Omega$ Terminations are connected  A1/B1 50 $\Omega$ Terminations are disconnected	SCL2 SDA2	L	HPD_SINK

Note. H: logic high; L: logic low.



**Table-1-2: Source Selection Lookup (Normal operation)** 

	CONTROL PINS			I/O SELECTED		HOT PLUG DETECT STATUS	
<b>S</b> 1	<b>S2</b>	PS	HPD_ctl	Y/Z	SCL_sink SDA_sink	HPD1 HPD2	
н	Н	L	I	A1/B1 $50\Omega$ Terminations are connected A2/B2 $50\Omega$ Terminations are disconnected	SCL1 SDA1	HPD_SINK	HPD_SINK
L	Н	L	Н	A2/B2 50Ω Terminations are connected  A1/B1 50Ω Terminations are disconnected	SCL2 SDA2	HPD_SINK	HPD_SINK

Note. H: logic high; L: logic low.



Table-1-3: Source Selection Lookup (Standby mode)

	CONTROL PINS			I/O SELECTE	ĒD	HOT PLUG DE	TECT STATUS
<b>S</b> 1	<b>S2</b>	PS	HPD_ctl	Y/Z	SCL_sink SDA_sink	HPD1	HPD2
Н	н	Н	L	A11/B11 are active  A12, B12, A13, B13, A14, B14, A2n, B2n are inactive	SCL1 SDA1	HPD_SINK	L
L	н	Н	L	A21/B21 are active  A22, B22, A23, B23, A24, B24, A1n, B1n are inactive	SCL2 SDA2	L	HPD_SINK

Note. H: logic high; L: logic low;



Table-1-4: Source Selection Lookup (Standby mode)

(	CONTROL PINS			I/O SELECTI	ED	HOT PLUG DE	TECT STATUS
<b>S</b> 1	<b>S</b> 2	PS	HPD_ctl	Y/Z	SCL_sink SDA_sink	HPD1	HPD2
н	Н	н	Н	A11/B11 are active  A12, B12, A13, B13, A14, B14, A2n, B2n are inactive	SCL1 SDA1	HPD_SINK	HPD_SINK
L	Ħ	н	н	A21/B21 are active  A22, B22, A23, B23, A24, B24, A1n, B1n are inactive	SCL2 SDA2	HPD_SINK	HPD_SINK

Note. H: logic high; L: logic low;

**Table-1-5: Source Selection Lookup (Shutdown mode)** 

	CONTROL PINS		I/O SE	LECTED	HOT PLUG DETECT STATUS		
<b>S</b> 1	<b>S</b> 2	PS	HPD_ctl	Y/Z	SCL_sink SDA_sink	HPD1	HPD2
Н	L	L	Ħ	A/B are all inactive	Be pulled high by external pull-up termination	HPD_SINK	HPD_SINK

Note. H: logic high; L: logic low;



#### **ABSOLUTE MAXIMUM RATINGS**

			UNIT
Supply voltage range	VCC	-0.5V to 4V	
	Anm, Bnm 2.5V to 4V		
Voltage range	Ym, Zm, VSADJ, EQ, HPDn, PS, CEC_A, CEC_D	m, Zm, VSADJ, EQ, HPDn, PS, HPD_ctl, cEC A, CEC D	
	SCLn, SCL_SINK, SDAn, SDA_S HPD_SINK, S1, S2, S3, WPn	-0.5V to 5.5V	
	System level (direct contact) (1)	Anm, Bnm, SCLn, SDAn, HPDn,	+/-6 KV
Electrostatic discharge	Human body model (2)	Anm, Bnm, SCLn, SDAn, HPDn	+/- 8 KV
		All pins	+/- 4 KV
	Machine model (2)	All pins	+/- 200V
	Charged-device model (2)	All pins	+/- 1000V

<sup>\*(1)</sup> System level: tested in accordance with IEC61000-4-2

## **RECOMMENDED OPERATING CONDITIONS**

	MIN	NOM	MAX	UNIT
VCC Supply voltage	3.135	3.3	3.465	V
T <sub>A</sub> Operating free-air temperature	0	25	70	°C
TMDS differential pins				
V <sub>IC</sub> Input common mode voltage	VCC-0.4		VCC+0.01	V
V <sub>ID</sub> Receiver peak-to-peak differential input voltage	150		1560	$mV_{P-P}$
R <sub>VSADJ</sub> Resistor for TMDS compliant voltage swing range		6.2		ΚΩ
RP1 Resistor for TMDS calibration		0		Ω
RP2 Resistor for TMDS calibration		100		ΚΩ
RP3 Resistor for TMDS calibration		0		Ω
EQ Resistor for TMDS equalization calibration		0		Ω
AV <sub>CC</sub> TMDS output termination voltage		3.3		V
R <sub>T</sub> Termination resistance	45	50	55	Ω
Signaling rate	0		2.5	Gbps
Control pins (PS, HPD_ctl)				
V <sub>IH</sub> LVTTL High-level input voltage	2		VCC	V
V <sub>IL</sub> LVTTL Low-level input voltage	GND		0.8	V
DDC I/O pins				
V <sub>I(DDC)</sub> DDC input voltage	GND		5.5	V
CE capacitor		0.1u		F
RESET capacitor		0.1u		F
Status and source selector pins (S1, S2, S3, HPD_SI	NK)	-		
V <sub>IH</sub> LVTTL High-level input voltage	1.5		5.5	V
V <sub>IL</sub> LVTTL Low-level input voltage	GND		0.8	V

<sup>\*(2)</sup> Tested in accordance with JEDEC Standard 22



## **Electrical Characteristics**

# Over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDI	•	MIN	TYP (1)	MAX	UNIT
		$R_T = 50 \Omega$ VCC = 3.3V $AV_{CC} = 3.3V$	S1/S2= L/H H/H PS=L		200		mA
I <sub>CC</sub> Supply current		Data pattern	S1/S2= H/L		5		mA
		= 2.5 Gbps Clock = 250 MHz	S1/S2= L/H H/H PS=H		10		mA
TMDS DIFFERENTIA	AL PINS (A	/B; Y/Z)					
V <sub>OH</sub> Single-ended h output Voltage	-	R <sub>T</sub> = 50 Ω		AVCC -10	AVCC	AVCC +10	mV
V <sub>OL</sub> Single-ended lo		VCC = 3.3V $AV_{CC} = 3.3V$		AVCC -700	AVCC -560	AVCC - 400	mV
V <sub>swing</sub> Single-ended o swing voltage	utput	7 11 00 010 1		400	560	700	mV
I <sub>(os)</sub> Short circuit out current	put				11.5	14	mA
R <sub>INT</sub> Input termination	on	$V_{IN} = 2.9 \text{ V}$		45	50	55	Ω
STATUS AND SOUR	CE						
SELECTOR PINS							
V <sub>IH</sub> TTL High-level i voltage	nput			2.5		5.5	V
V <sub>IL</sub> TTL Low-level ir voltage	nput			GND		0.8	V



# **Electrical Characteristics (continued)**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DDC I/O PINS					
C <sub>IO(sink)</sub> Input/output capacitance	V <sub>I(PP)</sub> = 1V, 100 kHz		10		pF
V <sub>IH(sink)</sub> High-level input voltage		2.0		5.5	V
V <sub>IL(sink)</sub> Low-level input voltage		GND		0.8	V
C <sub>IO (port 1:4)</sub> Input/output capacitance	V <sub>I(PP)</sub> = 1V, 100 kHz		6		pF
V <sub>IH(port 1:4)</sub> High-level input voltage		2.0		5.5	V
V <sub>IL(port 1:4)</sub> low-level input voltage		GND		0.8	V
STATUS AND SOURCE SELECTO					
V <sub>IH</sub> TTL High-level input voltage		2.5		5.5	V
V <sub>IL</sub> TTL Low-level input voltage		GND		8.0	V

 <sup>(1)</sup> All typical values are at 25 °C and with a 3.3-V VCC supply.



#### **SWITCHING CHARACTERISTICS**

# Over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP <sub>(1)</sub>	MAX	UNIT
TMDS DIFFERENTIAL PINS (Y/Z)					
t <sub>PLH</sub> Propagation delay time, low-to-high-level output			1200	1500	ps
t <sub>PHL</sub> Propagation delay time, high-to-low-level output			1200	1500	ps
t <sub>r</sub> Differential output signal rise time	$R_T = 50 \Omega$	75		240	ps
t <sub>f</sub> Differential output signal fall time	$AV_{CC} = 3.3V$	75		240	ps
t <sub>sk(p)</sub> Pulse skew (t <sub>PHL</sub> -t <sub>PLH</sub> )	Am/Bm (1) = 250 MHz clock		10	50	ps
t <sub>sk(D)</sub> Intra-pair differential skew	Am/Bm (2:4) = 2.5 Gbps pattern		20	40	ps
t <sub>sk(0)</sub> Inter-pair differential skew	2.5 00/0 / 2.110.11		18	65	ps
t <sub>jt(PP)</sub> Peak-to-peak output jitter(Y1/Z1)			40	50	ps
t <sub>jt(PP)</sub> Peak-to-peak output jitter (Y2/Z2; Y3/Z3;Y4/Z4)			75	120	ps
t <sub>sx</sub> Select to switch output			25	60	ns

<sup>\*(1)</sup> All typical values are at 25 $^{\circ}$ C and with a 3.3-V VCC supply.



#### **Memory Features**

- Operation Voltage VCC: 3.0V to 3.6V
- 2-wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bi-directional Data Transfer Protocol
- 100 kHz Compatibility
- Write Protect Pin for Hardware Data Protection
- 1-byte Write Modes
- Self-timed Write Cycle (5 ms max)

High-reliability

-Endurance: 10,000 Write Cycles

-Data Retention: 10 Years

#### **Absolute Maximum Ratings for Memory**

Operating Temperature (Plastic Package)	-40°ℂ to +125°ℂ
Storage Temperature (Plastic Package)	-40°C to +150°C
Voltage on WPn Pins with Respect to Ground	-1.0V to 5.5V
Maximum Operating Voltage	3.6V
DC Output Current	5.0mA

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### **Description**

The AZHW271D provides 2048 bits of serial electrically erasable and programmable memory organized as 256 words of 8 bits each. The device is optimized for use in industrial and commercial applications where low-power and low-voltage operations are essential.

#### Other Description

SERIAL CLOCK (SCL): The SCL input is used to positive edge clock data into each memory device and negative edge clock data out of each device.

SERIAL DATA (SDA): The SDA pin is bi-directional for serial data transfer.

**DEVICE/PAGE ADDRESSES (A0)**: The A0 is device address for EDID function that is hard wired for the memory.

## **Memory Organization**

**2K Serial memory:** Internally organized with 1 pages of 256 bytes each, the 2K requires an 8-bit data word address for random word addressing.

WRITE PROTECT (WP): The Write Protect pin provides hardware data protection. The Write Protect pin allows normal read/write operations when connected to ground (GND). When the Write Protect pin is connected to V<sub>DD</sub>, the write protection feature is enabled.

# Write Protect Description

WP Pin Status	Part of the Array Protected	
WP= V <sub>cc</sub>	Full (2K) Array	
WP=GND	Normal Read/Write Operations	



#### **DC Characteristics**

Applicable over recommended operating range from:  $T_A$ =-40 $^{\circ}$ C to +85 $^{\circ}$ C,  $V_{cc}$ =+3.0V to +3.6V, (unless otherwise noted).

Symbol	Parameter	Test Condition	Min	Тур	Max	Units
$V_{cc}$	Supply Voltage		3.0		3.6	V
I <sub>cc1</sub>	Supply Current	V <sub>cc</sub> =3.3V, Read at 100K		0.4	1.0	mA
I <sub>cc2</sub>	Supply Current	$V_{cc}$ =3.3V, Write at 100K		2.0	5.0	mA
I <sub>SB1</sub>	Standby Current	$V_{cc}$ =3.0V, $V_{IN}$ = $V_{cc}$ / $V_{ss}$			1.0	$\mu$ A
I <sub>SB2</sub>	Standby Current	$V_{cc}$ =3.6V, $V_{IN}$ = $V_{cc}$ / $V_{ss}$			6.0	$\mu$ A
I <sub>LI</sub>	Input Leakage Current	$V_{IN} = V_{cc} / V_{ss}$		0.10	3.0	$\mu$ A
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = V_{cc} / V_{ss}$		0.05	3.0	$\mu$ A
$V_{\rm IL}^{-1}$	Input Low Level		-0.6		V <sub>cc</sub> ×0.3	V
$V_{\rm IH}^{-1}$	Input High Level		V <sub>cc</sub> ×0.7		V <sub>cc</sub> +0.5	V
$V_{OL}$	Output Low Level	$V_{cc}$ =3.0V, $I_{OL}$ =2.1 mA			0.4	V

## AC Characteristics (As shown in Fig. 1. and Fig. 2.)

Applicable over recommended operating range from:  $T_A$ =-40 $^{\circ}$ C to +85 $^{\circ}$ C,  $V_{cc}$ =+3.0V to +3.6V CL=1 TTL Gate and 100pF (unless otherwise noted). Test conditions are listed in Note 2.

Symbol	Parameter	3.0-volt		3.6-volt		Units
Syllibol	F al allietei	Min	Max	Min	Max	Ullits
f <sub>SCL</sub>	Clock Frequency, SCL		100		100	kHz
$t_LOW$	Clock Pulse Width Low	4.7		4.7		$\mu$ s
t <sub>HIGH</sub>	Clock Pulse Width High	4.0		4.0		$\mu$ s
t <sub>AA</sub>	Clock Low to Data Out Valid	0.1	4.5	0.1	4.5	$\mu$ s
t <sub>BUF</sub> 1	Time the bus must be free before a new transmission can Start	4.7		4.7		$\mu$ s
t <sub>HD.STA</sub>	Start Hold Time	4.0		4.0		$\mu$ s
t <sub>SU.STA</sub>	Start Setup Time	4.7		4.7		$\mu$ s
t <sub>HD.STA</sub>	Data In Hold Time	0		0		$\mu$ s
t <sub>SU.DAT</sub>	Data In Setup Time	200		200		ns
t <sub>R</sub>	Inputs Rise Time		1.0		1.0	$\mu$ s
t <sub>F</sub>	Inputs Fall Time		300		300	ns
t <sub>SU.STO</sub>	Stop Setup Time	4.7		4.7		$\mu$ s
t <sub>DH</sub>	Data Out Hold Time	100		100		ns
t <sub>WR</sub>	Write Cycle Time		5		5	ms
Endurance <sup>1</sup>	3.3V, 25℃, Page Mode	10,000			Write Cycles	

Notes: 1. This parameter is characterized and is not 100% tested.

2. AC measurement conditions:

RL (connects to VDD = 5V):  $4.7k\Omega$ .

Input and output timing reference voltages: 0.5V<sub>DD</sub>

Input pulse voltages:  $0.3 V_{DD}$  to  $0.7 V_{DD}$ 

Input rise and fall times: ≤50ns



#### **Device Operation**

CLOCK and DATA TRANSITIONS: The SDA pin is normally pulled high with an external device. Data on the SDA pin may change only during SCL low time periods (refer to Figure 3). Data changes during SCL high periods will indicate a start or stop condition as defined below.

**START CONDITION:** A high-to-low transition of SDA with SCL high is a start condition which must precede any other command (refer to Figure 4).

**STOP CONDITION:** A low-to-high transition of SDA with SCL high is a stop condition. After a read sequence, the stop command will place the memory in a standby power mode (refer to Figure 4).

All addresses and data words are serially transmitted to and from the memory in 8-bit words. The memory sends a zero to acknowledge that it has received each word. This happens during the ninth clock cycle. Following receipt each word from the memory, the microcontroller should send a zero to memory and continue to output the next data word or send a stop condition to finish the read cycle (refer to Figure 5).

**STANDBY MODE:** The memory features a low-power standby mode which is enabled: (a) upon power-up and (b) after the receipt of the stop bit and the completion of any internal operations.

**DEVICE RESET:** After an interruption in protocol, power loss or system reset, any 2-wire part can be protocol reset by following these steps:

- 1. Clock up to 9 cycles.
- Look for SDA high in each cycle while SCL is high.
- 3. Create a start condition.

#### **Device Addressing**

The 2K memory device requires an 8-bit device address word following a start condition to enable the chip for a read or write operation.

The device address word consists of a mandatory one, zero sequence for the first four most significant bits as shown. This is common to all the memory devices.

The next 3 bits are the 0, 0 and 0 device address bits for the memory. These 3 bits must compare to their corresponding hard-wired input pins.

The eighth bit of the device address is the read/write operation select bit. A read operation is initiated if this bit is high and a write operation is initiated if this bit is low (refer to Figure 6).

Upon a compare of the device address, the memory will output a zero. If a compare is not made, the chip will return to a standby state.

## Write Operations

BYTE WRITE: A write operation requires an 8-bit data word address following the device address word and acknowledgment. Upon receipt of this address, the memory will again respond with a zero and then clock in the first 8-bit data word. Following receipt of the 8-bit data word, the memory will output a zero and the addressing device, such as a



microcontroller, must terminate the write sequence with a stop condition. At this time the memory enters an internally timed write cycle,  $t_{WR}$ , to the nonvolatile memory. All inputs are disabled during this write cycle and the memory will not respond until the write is complete (refer to Figure 7).

**PAGE WRITE**: The 2K memory is capable of a 256-byte page write.

A page write is initiated the same as a byte write, but the microcontroller does not send a stop condition after the first data word is clocked in. Instead, after the memory acknowledges receipt of the first data word, the microcontroller can transmit up to seven data words. The memory will respond with a zero after each data word received. The microcontroller must terminate the page write sequence with a stop condition (refer to Figure 8).

The data word address lower three bits are internally incremented following the receipt of each data word. The higher data word address bits are not incremented, retaining the memory page row location. When the word address, internally generated, reaches the page boundary, the following byte is placed at the beginning of the same page. If more than eight data words are transmitted to the memory, the data word address will "roll over" and previous data will be overwritten.

**ACKNOWLEDGE POLLING:** Once the internally timed write cycle has started and the memory inputs are disabled, acknowledge polling can be initiated. This involves sending a start condition followed by

the device address word. The read/write bit is representative of the operation desired. Only if the internal write cycle has completed will the memory respond with a zero allowing the read or write sequence to continue.

#### **Read Operations**

Read operations are initiated the same way as write operations with the exception that the read/write select bit in the device address word is set to one. There are three read operations: current address read, random address read and sequential read.

current address read: The internal data word address counter maintains the last address accessed during the last read or write operation, incremented by one. This address stays valid between operations as long as the chip power is maintained. The address "roll over" during read is from the last byte of the last memory page to the first byte of the first page. The address "roll over" during write is from the last byte of the current page to the first byte of the same page.

Once the device address with the read/write select bit set to one is clocked in and acknowledged by the memory the current address data word is serially clocked out. The microcontroller does not respond with an input zero but does generate a following stop condition (refer to Figure 9).

**RANDOM READ:** A random read requires a "dummy" byte write sequence to load in the data word address. Once the device address word and data word address are clocked in and acknowledged by the memory, the microcontroller must generate another start

condition. The microcontroller now initiates a current address read by sending a device address with the read/write select bit high. The memory acknowledges the device address and serially clocks out the data word. The microcontroller does not respond with a zero but does generate a following stop condition (refer to Figure 10).

**SEQUENTIAL READ:** Seguential reads are initiated by either a current address read or a address read. After the random microcontroller receives a data word, it responds with an acknowledge. As long as the memory receives an acknowledge, it will continue to increment the data word address and serially clock out sequential data words. When the memory address limit is reached, the data word address will "roll over" and the sequential read will continue. The sequential read operation is terminated when the microcontroller does not respond with a zero but does generate a following stop condition (refer to Figure 11).

Fig.1. Bus Timing Definition

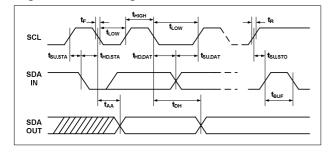
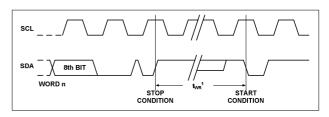


Fig. 2. SCL: Serial Clock, SDA: Serial Data I/O



Note: 1. The write cycle time  $t_{WR}$  is the time from a valid stop condition of a write sequence to the end of the internal clear/write cycle.

Fig. 3. Data Validity

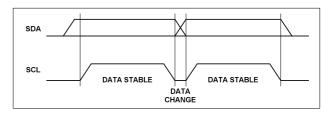


Fig. 4. Start and Stop Definition

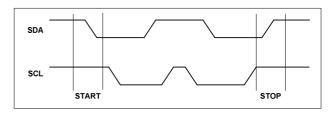


Fig. 5. Output Acknowledge

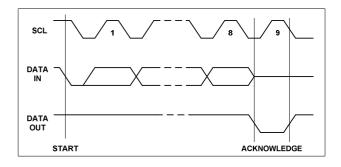


Fig. 6. Device Address

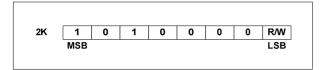


Fig. 10. Random Read

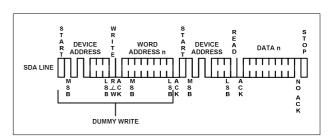


Fig. 7. Byte Write

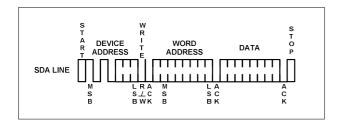


Fig. 11. Sequential Read

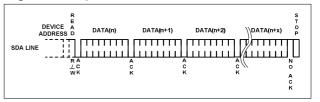


Fig. 8. Page Write

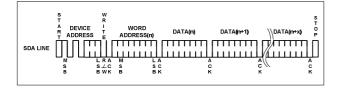
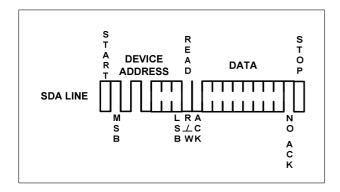
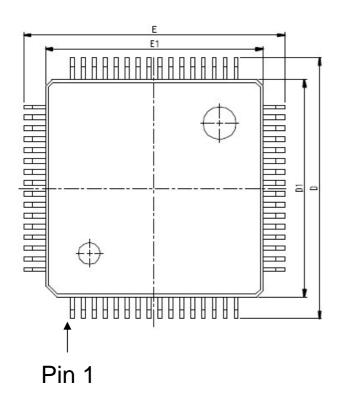


Fig. 9. Current Address Read



# 64-pin LQFP PACKAGE DIAGRAMS

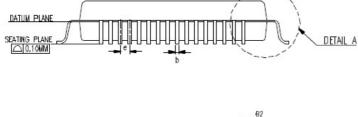
#### **TOP VIEW**

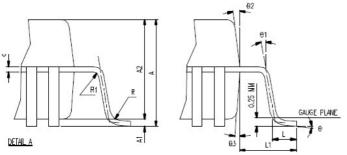


DAIDDL	DIMENSION IN MM			DIMENSION IN INCH			
SYMBOL	MIN.	NOM.	MAX.	MIN. NOM.		MAX.	
Α			1.60			0.063	
A1	0.05		0,15	0,002		0.006	
A2	1.35	1.40	1.45	0.053	0.055	0.057	
ь	0.17	D.20	0.23	0.007	0.008	0.009	
С	0.09		0.16	0.004		0.000	
e	0.	.50 BASK	C	0.020 BASIC			
D	1	2.00 BAS	SKC .	0,472 BASIC			
D1	1	10.00 BASIC			0.394 BASIC		
Ε	12.00 BASIC			D.472 BASIC			
E1	10.00 BASIC			0.394 BASIC			
L	0.45	0.60	0.75	0.018	0.024	0.030	
L1	1.00 REF.			0,039 REF.			
R1	80.0			0.003			
R	80.0		0.20	0.003		0.008	
θ	0	3.5	7	0 3.5		7	
<del>0</del> 1	0		(3)	0			
<del>0</del> 2	11	12	13	11	12	13	
<del>0</del> 3	11	12	13	11	12	13	
JEDEC	MS-026 (BCD)						

▲ \*NOTES: DIMENSIONS " D1 " AND " E1 " D0 NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSIN IS 0.25 mm PER SIDE. " D1 " AND " E1 " ARE MAXIMUM PLASTIC BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH.

#### SIDE VIEW





# **Marking Code**

Part Number	Marking Code	
AZHW271D	AZHW271D	



# **Revision History**

Revision	Modification Description		
Revision 2011/05/22	Preliminary Release.		
Revision 2011/08/09	Formal Release.		